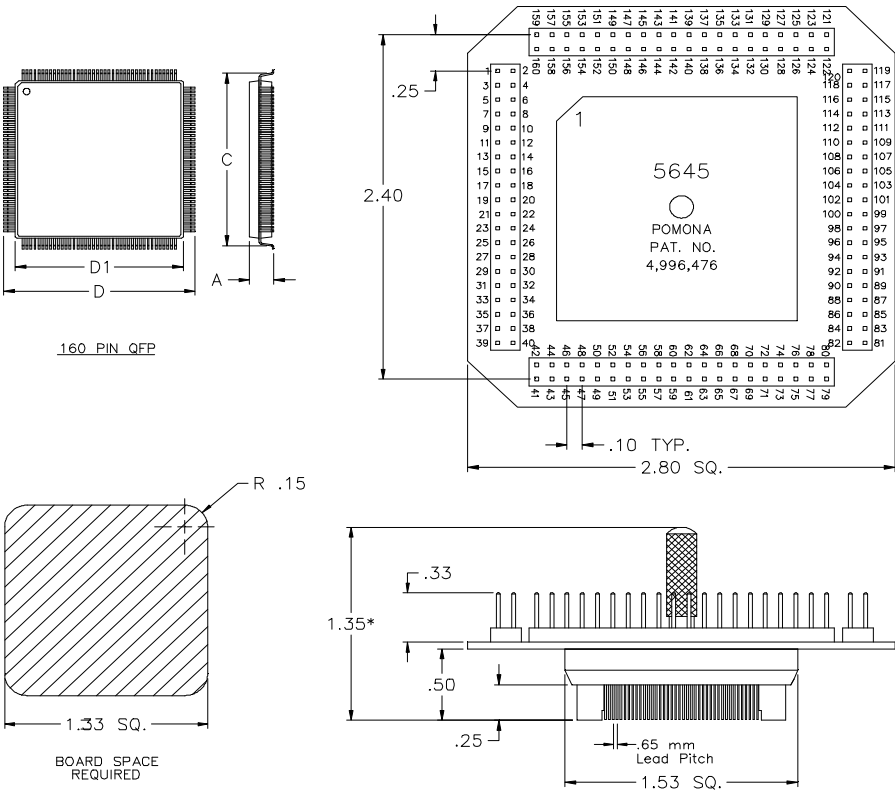


Model Model 5645 & 5645-2  
160 Pin EIAJ QFP Test Clip  
0.65mm Lead Pitch

These new test clips provide the user with an easy means to connect instrumentation to the fine pitch QFP chip leads.

- Interfaces with high density 160 Pin EIAJ QFP surface mount chip leads.
- Two stage alignment assures positive connections.
- Gold plated connector pins and contacts assure noise free connections.
- Gold plated .025" square pins provide easy connection with either ribbon cable or discrete jumpers.

Pomona's EIAJ test clips are perfect for system design, field service testing, failure analysis, and for use with logic analyzers.



Other clips are also available in other sizes to fit the most popular EIAJ chips now in use.

Pomona offers a test clip to fit the most commonly found variations on the EIAJ specifications.

| Leads<br>"D" | Body<br>"D1" | Lead<br>Interface<br>"C" | Chip<br>Height<br>"A" | Pomona<br>Part Number |
|--------------|--------------|--------------------------|-----------------------|-----------------------|
| 31.9mm       | 28.0mm       | 30.3mm<br>(1.193")       | 3.4mm                 | 5645                  |
| 31.2mm       | 28.0mm       | 29.6mm<br>(1.165")       | 3.4mm                 | 5645-2                |

All dimensions are in inches. Tolerances (except noted): .xx = ±.02" (.51 mm), .xxx = ± .005" (.127 mm).  
All specifications are to the latest revisions. Specifications are subject to change without notice.  
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